Operational Amplifier, Low Power, 1.2 MHz, 42 μA

NCS20081/2/4, NCV20081/2/4

The NCS20081/2/4 is a family of single, dual and quad Operational Amplifiers (Op Amps) with 1.2 MHz of Gain–Bandwidth Product (GBWP) While consuming only 42 μA of Quiescent current per opamp. The NCS2008x has Input Offset Voltage of 4 mV and operates from 1.8 V to 5.5 V supply voltage over a wide temperature range (–40°C to +125°C). The Rail–to–Rail In/Out operation allows the use of the entire supply voltage range while taking advantage of the 1.2 MHz GBWP. Thus, this family offers superior performance over many industry standard parts. These devices are AEC–Q100 qualified which is denoted by the NCV prefix.

NCS2008x's low current consumption and low supply voltage performance in space saving packages, makes them ideal for sensor signal conditioning and low voltage current sensing applications in Automotive, Consumer and Industrial markets.

Features

- Wide Bandwidth: 1.2 MHz
- Low Supply Current/ Channel: $42 \mu A \text{ typ } (V_S = 1.8 \text{ V})$
- Low Input Offset Voltage: 4 mV max
 Wide Supply Range: 1.8 V to 5.5 V
- Wide Temperature Range: -40°C to +125°C
- Rail-to-Rail Input and Output
- Unity Gain Stable
- Available in Single, Dual and Quad Packages
- NCV Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q100 Qualified and PPAP Capable
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

Applications

- Automotive
- Battery Powered/ Portable
- Sensor Signal Conditioning
- Low Voltage Current Sensing
- Filter Circuits
- Unity Gain Buffer



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SC70-5 CASE 419A

TSOP-5/SOT23-5 CASE 483





Micro8/MSOP8 CASE 846A

SOIC-8 CASE 751





TSSOP-8 CASE 948S

TSSOP-14 CASE 948G





SOIC-14 CASE 751A

UDFN6 CASE 517AP

DEVICE MARKING INFORMATION

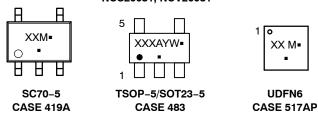
See general marking information in the device marking section on page 2 of this data sheet.

ORDERING INFORMATION

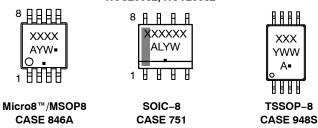
See detailed ordering and shipping information on page 3 of this data sheet.

MARKING DIAGRAMS

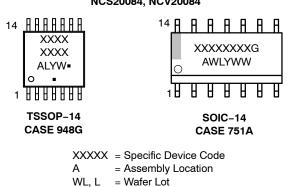
Single Channel Configuration NCS20081, NCV20081



Dual Channel Configuration NCS20082, NCV20082



Quad Channel Configuration NCS20084, NCV20084



G or ■ = Pb–Free Package
(Note: Microdot may be in either location)

Y = Year WW, W = Work Week

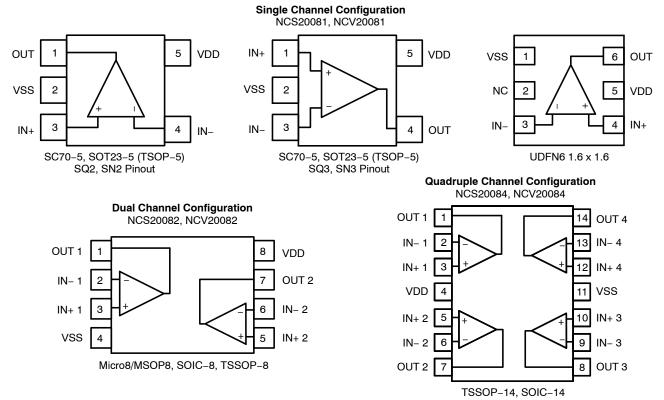


Figure 1. Pin Connections

ORDERING INFORMATION

Device	Configuration	Automotive	Marking	Package	Shipping [†]
NCS20081SQ2T2G			AAX	SC70	
NCS20081SQ3T2G	1		AAP	SC70	
NCS20081SN2T1G	1	No	AER	SOT23-5/TSOP-5	
NCS20081SN3T1G	1		AEU	SOT23-5/TSOP-5	
NCS20081MUTAG	Single		AP	UDFN6	
NCV20081SQ2T2G*	1		AAX	SC70	
NCV20081SQ3T2G*	1	Va a	AAP	SC70	
NCV20081SN2T1G*	1	Yes	AER	SOT23-5/TSOP-5	
NCV20081SN3T1G*	1		AEU	SOT23-5/TSOP-5	
NCS20082DMR2G			2K82	Micro8/MSOP8	Contact local sales office for more information
NCS20082DR2G	1	No	NCS20082	SOIC-8	more information
NCS20082DTBR2G	Dural		K82	TSSOP-8	
NCV20082DMR2G*	Dual		2K82	Micro8/MSOP8	
NCV20082DR2G*	1	Yes	NCS20082	SOIC-8	
NCV20082DTBR2G*	1		K82	TSSOP-8	
NCS20084DR2G		NI-	20084	SOIC-14	
NCS20084DTBR2G		No	284	TSSOP-14	
NCV20084DR2G*	Quad	.,	20084	SOIC-14	
NCV20084DTBR2G*]	Yes	284	TSSOP-14	

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D

^{*}NCV Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q100 Qualified and PPAP Capable.

ABSOLUTE MAXIMUM RATINGS (Note 1)

Rating	Symbol	Limit	Unit
Supply Voltage (V _{DD} – V _{SS}) (Note 2)	V _S	6	V
Input Voltage	VI	V _{SS} – 0.5 to V _{DD} + 0.5	V
Differential Input Voltage	V_{ID}	±V _S	V
Maximum Input Current	l _l	±10	mA
Maximum Output Current	Io	±100	mA
Continuous Total Power Dissipation (Note 2)	P _D	200	mW
Maximum Junction Temperature	T_J	150	°C
Storage Temperature Range	T _{STG}	-65 to 150	°C
Mounting Temperature (Infrared or Convection – 20 sec)	T _{mount}	260	°C
ESD Capability (Note 3) Human Body Model Charge Device Model	ESD _{HBM} ESD _{CDM}	2000 2000	V
Latch-Up Current (Note 4)	I _{LU}	100	mA
Moisture Sensitivity Level (Note 5)	MSL	Level 1	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- 1. Refer to ELECTRICAL CHARACTERISTICS for Safe Operating Area.
- 2. Continuous short circuit operation to ground at elevated ambient temperature can result in exceeding the maximum allowed junction temperature of 150°C. Output currents in excess of the maximum output current rating over the long term may adversely affect reliability. Shorting output to either VDD or VSS will adversely affect reliability.
- 3. This device series incorporates ESD protection and is tested by the following methods: ESD Human Body Model tested per JEDEC standard Js-001-2017 (AEC-Q100-002) ESD Charged Device Model tested per JEDEC standard JS-002-2014 (AEC-Q100-011)
- 4. Latch-up Current tested per JEDEC standard JESD78E (AEC-Q100-004)
- 5. Moisture Sensitivity Level tested per IPC/JEDEC standard: J-STD-020A

THERMAL INFORMATION

Parameter	Symbol	Channels	Package	Single Layer Board (Note 6)	Multi-Layer Board (Note 7)	Unit
			SC-70	491	444	
		Single	SOT23-5/TSOP-5	310	247	
			UDFN6	278	239	
Junction to Ambient	_	Dual	Micro8/MSOP8	236	167	
Thermal Resistance	$\theta_{\sf JA}$		SOIC-8	190	131	°C/W
			TSSOP-8	253	194	
		Quad	SOIC-14	130	99	
			TSSOP-14	178	140	

- 6. Value based on 1S standard PCB according to JEDEC51-3 with 1.0 oz copper and a 300 mm² copper area
- 7. Value based on 1S2P standard PCB according to JEDEC51-7 with 1.0 oz copper and a 100 mm² copper area

OPERATING RANGES

Parameter	Symbol	Min	Max	Unit
Operating Supply Voltage	V _S	1.8	5.5	V
Differential Input Voltage	V_{ID}		V _S	V
Input Common Mode Range	V_{ICM}	V _{SS} – 0.2	V _{DD} + 0.2	V
Ambient Temperature	T _A	-40	125	°C

Functional operation above the stresses listed in the Recommended Operating Ranges is not implied. Extended exposure to stresses beyond the Recommended Operating Ranges limits may affect device reliability.

ELECTRICAL CHARACTERISTICS AT V_S = 1.8 V T_A = 25°C; R_L \geq 10 kΩ; V_{CM} = V_{OUT} = mid–supply unless otherwise noted. **Boldface** limits apply over the specified temperature range, T_A = -40°C to 125°C. (Note 8)

Parameter	Symbol	Cor	nditions	Min	Тур	Max	Unit
INPUT CHARACTERISTICS							
Input Offset Voltage	Vos				0.5	3.5	mV
			•			4	mV
Offset Voltage Drift	$\Delta V_{OS}/\Delta T$				1		μV/°C
Input Bias Current (Note 8)	I _{IB}				1		pА
			•			1500	pА
Input Offset Current (Note 8)	Ios				1		pА
			•			1100	рА
Channel Separation	XTLK	f =	= 1 kHz		125		dB
Differential Input Resistance	R_{ID}				10		GΩ
Common Mode Input Resistance	R _{IN}				10		GΩ
Differential Input Capacitance	C _{ID}				1		pF
Common Mode Input Capacitance	C _{CM}				5		pF
Common Mode Rejection Ratio	CMRR	V _{CM} = V _{SS} -	- 0.2 to V _{DD} + 0.2	48	73		dB
		V _{CM} = V _{SS} +	+ 0.2 to V _{DD} – 0.2	45			
OUTPUT CHARACTERISTICS							_
Open Loop Voltage Gain	A_{VOL}			86	120		dB
			•	80			
Short Circuit Current	I _{SC}	Output to positiv	ve rail, sinking current		15		mA
	•	Output to negativ	e rail, sourcing current		11		
Output Voltage High	V _{OH}		wing from positive rail		3	19	mV
		$V_{OH} = 0$	V _{DD} – V _{OUT}			20	
Output Voltage Low	V_{OL}	Voltage output sv	wing from negative rail		3	19	mV
		$V_{OL} = 0$	V _{OUT} - V _{SS}			20	
AC CHARACTERISTICS							_
Unity Gain Bandwidth	UGBW				1.2		MHz
Slew Rate at Unity Gain	SR	V _{IN} = 1.2	Vpp, Gain = 1		0.4		V/μs
Phase Margin	ψ_{m}				60		٥
Gain Margin	A _m				19		dB
Settling Time	t _S	V _{IN} = 1.2 Vpp,	Settling time to 0.1%		5		μs
		Gain = 1	Settling time to 0.01%		6		
Open Loop Output Impedance	Z _{OL}				See Figure 25		Ω
NOISE CHARACTERISTICS							
Total Harmonic Distortion plus Noise	THD+N	V _{IN} = 1.2 Vpp	o, f = 1 kHz, Av = 1		0.005		%
Input Referred Voltage Noise	e _n		= 1 kHz		30		nV/√Hz
		f =	10 kHz		24		-
Input Referred Current Noise	i _n	f = 1 kHz			300		fA/√Hz
SUPPLY CHARACTERISTICS					-		-
Power Supply Rejection Ratio	PSRR	N	o Load	67	90		dB
				64			
Power Supply Quiescent Current	I _{DD}	Per cha	nnel, no load		42	60	μΑ

^{8.} Performance guaranteed over the indicated operating temperature range by design and/or characterization.

ELECTRICAL CHARACTERISTICS AT V_S = **3.3 V** $T_A = 25^{\circ}\text{C}; \ R_L \ge 10 \ \text{k}Ω; \ V_{CM} = V_{OUT} = \text{mid-supply unless otherwise noted.}$ **Boldface** limits apply over the specified temperature range, $T_A = -40^{\circ}\text{C}$ to 125°C. (Note 9)

Parameter	Symbol	Со	nditions	Min	Тур	Max	Unit
INPUT CHARACTERISTICS							
Input Offset Voltage	Vos				0.5	3.5	mV
			,			4	mV
Offset Voltage Drift	$\Delta V_{OS}/\Delta T$				1		μV/°C
Input Bias Current (Note 9)	I _{IB}				1		pА
			,			1500	pА
Input Offset Current (Note 9)	los				1		pА
			,			1100	pА
Channel Separation	XTLK	f =	= 1 kHz		125		dB
Differential Input Resistance	R_{ID}				10		GΩ
Common Mode Input Resistance	R _{IN}				10		GΩ
Differential Input Capacitance	C _{ID}				1		pF
Common Mode Input Capacitance	C _{CM}				5		pF
Common Mode Rejection Ratio	CMRR	V _{CM} = V _{SS} -	- 0.2 to V _{DD} + 0.2	53	76		dB
		V _{CM} = V _{SS} -	+ 0.2 to V _{DD} – 0.2	48			
OUTPUT CHARACTERISTICS							
Open Loop Voltage Gain	A_{VOL}			90	120		dB
				86			
Short Circuit Current	I _{SC}	Output to positive	e rail, sinking current		15		mA
		Output to negativ	e rail, sourcing current		11		
Output Voltage High	V_{OH}	Voltage output s	wing from positive rail		3	24	mV
		V _{OH} =	V _{DD} – V _{OUT}			25	
Output Voltage Low	V_{OL}	Voltage output sv	wing from negative rail		3	24	mV
		V _{OL} =	V _{OUT} - V _{SS}			25	
AC CHARACTERISTICS							
Unity Gain Bandwidth	UGBW				1.2		MHz
Slew Rate at Unity Gain	SR	V _{IN} = 2.5	Vpp, Gain = 1		0.4		V/μs
Phase Margin	ψ_{m}				60		0
Gain Margin	A _m				18		dB
Settling Time	t _S	V _{IN} = 2.5 Vpp,	Settling time to 0.1%		5		μs
		Gain = 1	Settling time to 0.01%		6		
Open Loop Output Impedance	Z _{OL}				See Figure 25		Ω
NOISE CHARACTERISTICS	<u> </u>						
Total Harmonic Distortion plus Noise	THD+N	V _{IN} = 2.5 Vpr) f = 1 kHz Av = 1		0.005		%
Input Referred Voltage Noise	e _n	V _{IN} = 2.5 Vpp, f = 1 kHz, Av = 1 f = 1 kHz			30		nV/√Hz
mpar riolonea voltage riolos	911	f = 10 kHz			24		
Input Referred Current Noise	i _n	f = 1 kHz			300		fA/√Hz
SUPPLY CHARACTERISTICS	n'	1-					9 1112
Power Supply Rejection Ratio	PSRR	N	o Load	67	90		dB
	. 51111			64	-		-

 $^{9. \ \} Performance \ guaranteed \ over the \ indicated \ operating \ temperature \ range \ by \ design \ and/or \ characterization.$

ELECTRICAL CHARACTERISTICS AT V_S = **5.5 V** T_A = 25°C; R_L \geq 10 kΩ; V_{CM} = V_{OUT} = mid–supply unless otherwise noted. **Boldface** limits apply over the specified temperature range, T_A = -40°C to 125°C. (Note 10)

					1		1
Parameter	Symbol	Со	nditions	Min	Тур	Max	Unit
INPUT CHARACTERISTICS							
Input Offset Voltage	Vos				0.5	3.5	mV
						4	mV
Offset Voltage Drift	$\Delta V_{OS}/\Delta T$				1		μV/°C
Input Bias Current (Note 10)	I _{IB}				1		pА
						1500	pА
Input Offset Current (Note 10)	Ios				1		pА
						1100	pА
Channel Separation	XTLK	f :	= 1 kHz		125		dB
Differential Input Resistance	R_{ID}				10		GΩ
Common Mode Input Resistance	R _{IN}				10		GΩ
Differential Input Capacitance	C _{ID}				1		pF
Common Mode Input Capacitance	C _{CM}				5		pF
Common Mode Rejection Ratio	CMRR	V _{CM} = V _{SS}	– 0.2 to V _{DD} + 0.2	55	79		dB
		$V_{CM} = V_{SS}$	+ 0.2 to V _{DD} - 0.2	51			
OUTPUT CHARACTERISTICS							
Open Loop Voltage Gain	A_{VOL}			90	120		dB
			'	86			
Short Circuit Current	I _{SC}	Output to positive	ve rail, sinking current		15		mA
		Output to negative	re rail, sourcing current		11		
Output Voltage High	V _{OH}		wing from positive rail		3	24	mV
		V _{OH} =	V _{DD} – V _{OUT}			25	
Output Voltage Low	V_{OL}	Voltage output s	wing from negative rail		3	24	mV
		V _{OL} =	V _{OUT} - V _{SS}			25	
AC CHARACTERISTICS							-
Unity Gain Bandwidth	UGBW				1.2		MHz
Slew Rate at Unity Gain	SR	V _{IN} = 5	Vpp, Gain = 1		0.4		V/μs
Phase Margin	Ψm				60		0
Gain Margin	A _m				17		dB
Settling Time	t _S	V _{IN} = 5 Vpp,	Settling time to 0.1%		5		μs
		Gain = 1	Settling time to 0.01%		6		
Open Loop Output Impedance	Z _{OL}				See		Ω
					Figure 25		
NOISE CHARACTERISTICS					25		
Total Harmonic Distortion plus Noise	THD+N	V = 5 Vnn	f = 1 kHz, Av = 1		0.005		%
Input Referred Voltage Noise	e _n		= 1 kHz		30		nV/√Hz
input ricierred voltage rvoise	on I				24		110/ 1112
Input Referred Current Noise	+ +	f = 10 kHz f = 1 kHz			300		fA/√Hz
SUPPLY CHARACTERISTICS	i _n	I:	- I NIIZ		300		IAV VIIZ
Power Supply Rejection Ratio	PSRR	N	lo Load	67	90		dB
i owei ouppiy nejection natio	FONN	IN	io Loau		90		ub ub
Power Supply Quiescent Current		Dayaha	nnel, no load	64	40	70	^
10. Performance guaranteed over the in	I _{DD}		·		48	70	μΑ

10. Performance guaranteed over the indicated operating temperature range by design and/or characterization.

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

TYPICAL PERFORMANCE CHARACTERISTICS

 T_A = 25°C, $R_L \ge 10 \text{ k}\Omega$, V_{CM} = V_{OUT} = mid-supply unless otherwise specified

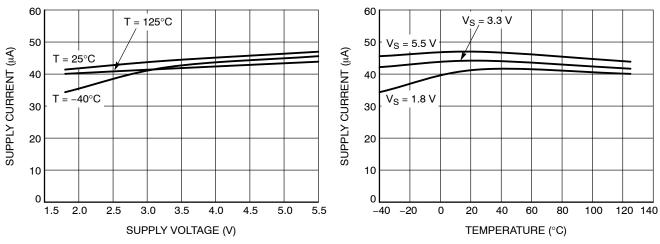


Figure 2. Quiescent Current per Channel vs. Supply Voltage

Figure 3. Quiescent Current vs. Temperature

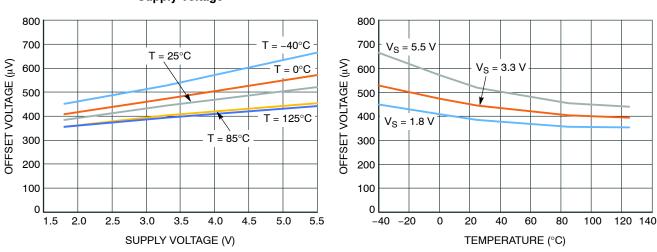


Figure 4. Offset Voltage vs. Supply Voltage

Figure 5. Offset Voltage vs. Temperature

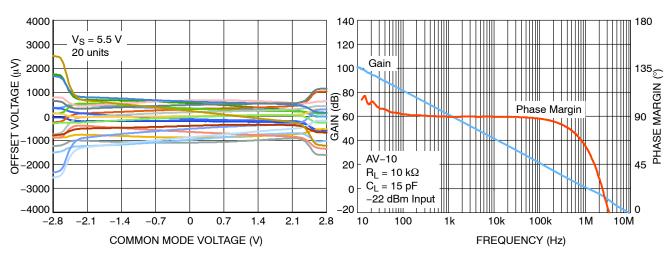
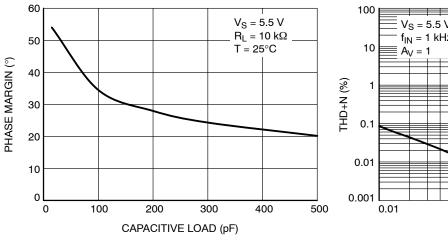


Figure 6. Offset Voltage vs. Common Mode Voltage

Figure 7. Open-loop Gain and Phase Margin vs. Frequency

TYPICAL PERFORMANCE CHARACTERISTICS

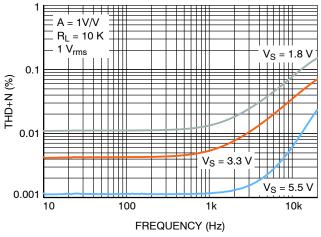
 T_A = 25°C, $R_L \ge 10 \text{ k}\Omega$, V_{CM} = V_{OUT} = mid-supply unless otherwise specified



100 V_S = 5.5 V f_{IN} = 1 kHz A_V = 1 0.01 0.001 0.001 0.01 0.1 1 OUTPUT VOLTAGE (Vrms)

Figure 8. Phase Margin vs. Capacitive Load

Figure 9. THD + N vs. Output Voltage



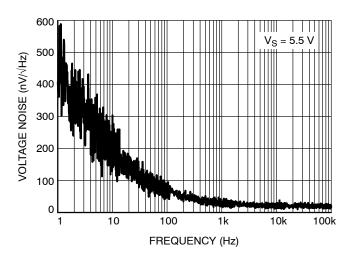
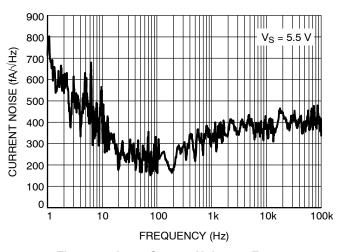


Figure 10. THD + N vs. Frequency

Figure 11. Input Voltage Noise vs. Frequency



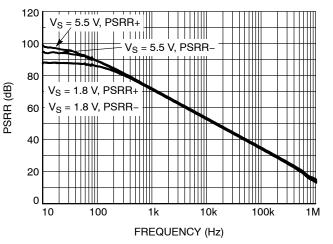


Figure 12. Input Current Noise vs. Frequency

Figure 13. PSRR vs. Frequency

TYPICAL PERFORMANCE CHARACTERISTICS

 T_A = 25°C, $R_L \ge$ 10 k $\Omega,~V_{CM}$ = V_{OUT} = mid-supply unless otherwise specified

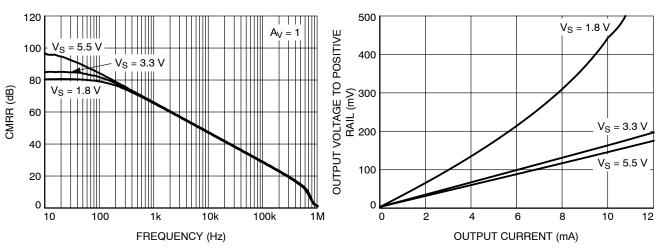


Figure 14. CMRR vs. Frequency

Figure 15. Output Voltage High to Rail

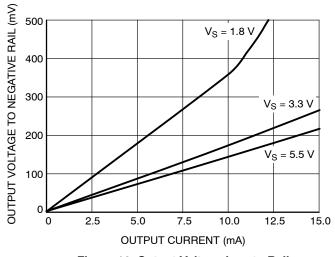


Figure 16. Output Voltage Low to Rail

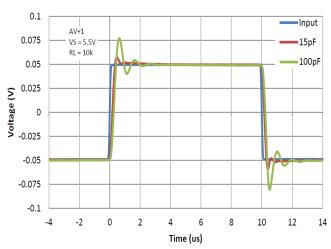


Figure 17. Non-Inverting Small Signal Transient Response

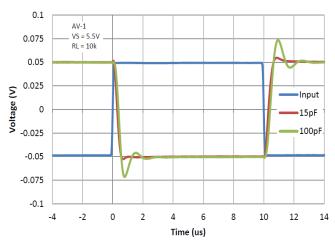


Figure 18. Inverting Small Signal Transient Response

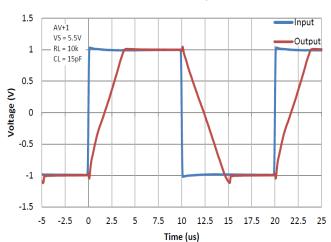


Figure 19. Non-Inverting Large Signal Transient Response

TYPICAL PERFORMANCE CHARACTERISTICS

 T_A = 25°C, $R_L \ge$ 10 k $\Omega,~V_{CM}$ = V_{OUT} = mid–supply unless otherwise specified

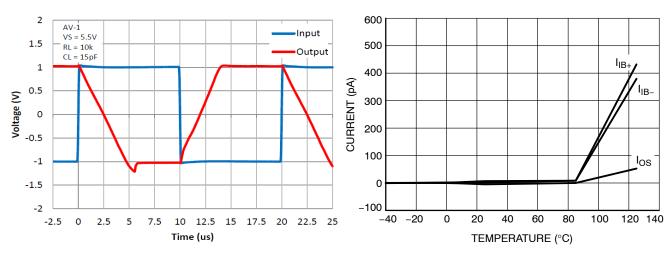


Figure 20. Inverting Large Signal Transient Response

Figure 21. Input Bias and Offset Current vs. Temperature

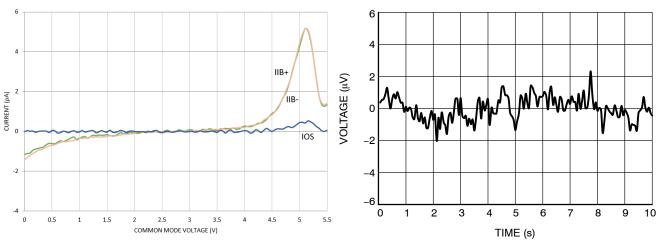


Figure 22. Input Bias Current vs. Common Mode Voltage

Figure 23. 0.1 Hz to 10 Hz Noise

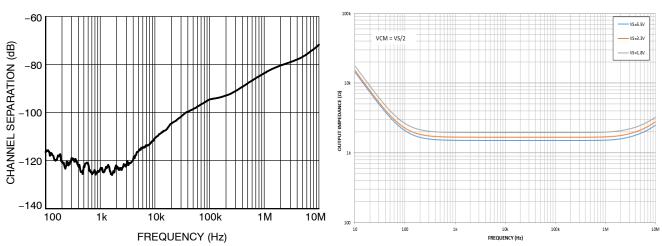


Figure 24. Channel Separation vs. Frequency

Figure 25. Open Loop Output Impedance vs. Frequency

TYPICAL PERFORMANCE CHARACTERISTICS

 T_A = 25°C, $R_L \ge 10~k\Omega, \, V_{CM}$ = V_{OUT} = mid–supply unless otherwise specified

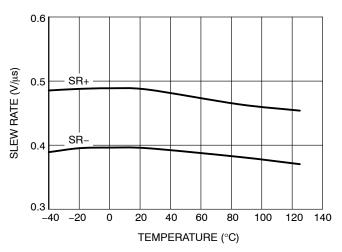


Figure 26. Slew Rate vs. Temperature

Application Information

The NCS/NCV20081/2/4 family of operational amplifiers is manufactured using ON Semiconductor's CMOS process. Products in this class are general purpose, unity–gain stable amplifiers and include single, dual and quad configurations.

Rail-to-Rail Input with No Phase Reversal

The NCS operational amplifiers are designed to prevent phase reversal or any similar issues when the input pins potential exceed the supply voltages by up to 100 mV. Figure 6 shows the input voltage exceeding the supply limits.

The input stage of the NCS/NCV 20081/2/4 family consists of two differential CMOS input stages connected in parallel: the first is constructed using paired PMOS devices and it operates at low common mode input voltages (VCM); the second stage is build using paired NMOS devices to operate at high VCM. The transition between the two input stages occurs at a common mode input voltage of approximately VDD–1.3V and it is visible in Figure 6 (Offset vs. VCM).

Limiting Input Voltages

In order to prevent damage and/or improper operation of these amplifiers, the application circuit must never expose the input pins to voltages or currents higher than the Absolute Maximum Ratings.

The internal ESD structure includes special diodes to protect the input stages while maintaining a low Input Bias (IIB) current. The input protection circuitry clamp the inputs when the signals applied exceed more than one diode drop

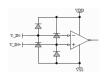
below VSS or one diode drop above VDD. Very fast ESD events (within the limits specified) trigger the protection structure so the operational amplifier is not damaged.

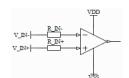
However, in some applications, it can be necessary to prevent excessive voltages from reaching the operational amplifier inputs by adding external clamp diodes. A possible solution is presented in Figure 27, where the four low-drop fast diodes (Shottky preferred) are used in parallel with the internal structure to divert the excessive energy to the supply rails where it can be easily dissipated or absorbed by the supply capacitors. The application designer should also take into account that these external diodes add leakage currents and parasitic capacitance that must be considered when evaluating the end-to-end performance of the amplifier stage.

Limiting Input Currents

In order to prevent damage/ improper operation of these amplifiers, the application circuit must limit the currents flowing in and out of the input pins. A possible solution is presented in Figure 27 by means of the two added series resistors. The minimum value for R_IN- and R_IN+ should be calculated using Ohm's Law so they limit the input pin currents to less than the absolute maximum values specified. The application designer should take into account that these resistors also add parasitic inductance that must be considered when evaluating performance.

Combining the current limiting resistors with the voltage limiting diodes creates a solid input protection structure, that can be used to insure reliable operation of the amplifier even in the hardest conditions.





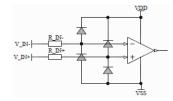


Figure 27. Typical Protection of the Operational Amplifier Inputs

Rail-to-Rail Output

The maximum output voltage swing is dependent of the particular output load. According to the specification, the output can reach within 25 mV of either supply rail when load resistance is 10 k Ω . Figure 15 and Figure 16 shows the load drive capabilities of the part under different conditions. Output current is internally limited to 15 mA typ.

Capacitive Loads

Driving capacitive loads can create stability problems for voltage feedback opamps, as it is a known possible cause for:

- degraded phase margin
- lowered bandwidth
- gain peaking of the frequency response
- overshoot and ringing of the step response.

While the NCS(V)20081/2/4 family of opamps are capable of driving capacitive loads up to 100 pF, adding a small resistor in series to the output (R_ISO in Figure 28) will increase the feedback loop's phase margin. This leads to higher stability by making the equivalent load more resistive at high frequencies.

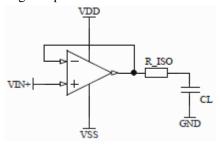


Figure 28. Driving Capacitive Loads

Simulating the application with ON Semiconductor's SPICE models is a good starting point for selecting the isolation resistor's value, and then bench testing the frequency and step response can be used to fine-tune the value according to the desired characteristic.

Unity Gain Bandwidth

Interfacing a high impedance sensor's output to a relatively low-impedance ADC input usually requires an intermediate stage to avoid unwanted interference of the two devices, and this stage needs to have a high input impedance, a low output impedance and high output current.

The unity gain buffer is recommended here (Figure 29). The ADC's internal sampling capacitor requires a buffer front—end to recharge it faster than the sampling time, and this problem is even worse if more channels are sampled by the same ADC using an internal multiplexer. In

order to achieve a settling time shorter than the multiplexed sampling rate, an RC stage is recommended between the buffer and the ADC input. The R resistor's value should be low enough to charge the capacitor quickly, but at the same time large enough to isolate the capacitive load from the opamp's output to preserve phase margin. When transients are generated by the sensor's output, first the two opamp's inputs see a high differential voltage between them, then the output settles and brings the inverting input back to the correct voltage.

To successfully accommodate for example a 0.1 V to 4 V sensor signal, the opamp's differential input range of the NCS(V) 20081/2/4 series is close to the supply range VDD-VSS, and the output will match the input. The differential input voltage is limited only by the ESD protection structure and not by back-to-back diodes between inputs.

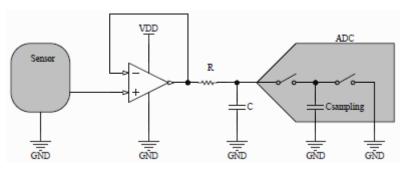


Figure 29. Unity Gain Buffer Stage for Sampling with ADC

Power Supply Bypassing

For AC, the power supply pins (VDD and VSS for split supply, VDD for single supply) should be bypassed locally with a quality capacitor in the range of 100 nF (ceramics are recommended for their low ESR and good high frequency response) as close as possible to the opamp's supply pins.

For DC, a bulk capacitor in the range of 1 µF within inches distance from the opamp can provide the increased currents required to drive higher loads.

Unused Operational Amplifiers

Occasionally not all the opamps offered in the quad packages are needed for a specific application. They can be connected as "buffering ground" as shown in Figure 30, a solution that does not need any extra parts. Connecting them differently (inputs split to rails, left floating, etc.) can sometimes cause unwanted oscillation, crosstalk, increased current consumption, or add noise to the supply rails.

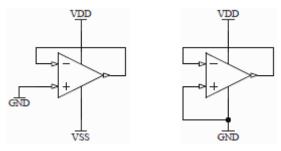


Figure 30. Unused Operational Amplifiers

PCB Surface Leakage

The Printed Circuit Board's surface leakage effects should be estimated if the lowest possible input bias current is critical. Dry environment surface current increases further when the board is exposed to humidity, dust or chemical contamination. For harsh environment conditions, protecting the entire board surface (with all the exposed metal pins and soldered areas) is advised. Conformal coating or potting the board in resin proves effective in most cases.

An alternate solution for reduced leakage is the use of guard rings around sensitive pins and pads. A proper guard ring should have low impedance and be biased to the same voltage as the sensitive pin so no current flows in between.

For an inverting amplifier, the non-inverting input is usually connected to supply's ground (or virtual ground at half the rail voltage in single supply applications) so it can represent a good ring solution. When routing the PCB traces, create a closed perimeter around the inverting input pad (which carries the signal) and connect it to the non-inverting input.

For a non-inverting amplifier, use a similarly shaped (rectangle or circle) copper trace around the non-inverting input pad (which carries the signal) and connect it to the inverting input pin, which presents a much lower impedance thanks to the feedback network.

PCB Routing Recommendations

Even when some operational amplifier is expected to amplify only the useful DC signal, it can also pick some high frequency noise altogether and amplify it accordingly, if the design allows it. In order to reach the specified operational amplifier parameters and to avoid high frequency interference issues, it is recommended that the PCB layout respects some basic guidelines:

- A dedicated layer for the ground plane should be used whenever possible and all supply decoupling capacitors should connect to it by vias.
- Copper traces should be as short as possible.
- High current paths should not be shared by small signal or low current traces.
- If present, switching power supply blocks should be kept away from the analog sensitive areas to avoid potential conducted and radiated noise issues.
- When different circuit taxonomies share the same board, it is recommended to keep separated the power areas, the digital areas and the small signal analog areas. Small-signal parts in the signal path should be placed as close as possible to the opamp's input pins.
- Metal shielding the sensitive areas and the "offender" blocks may be required in some cases.

In a sensitive application, a good PCB design can take longer but it will save troubleshooting time.

Applications Example

Second Order Active Low Pass Filter

Using an opamp with a low input bias current allows the use of higher value resistors and smaller capacitors for the same filter application. As a trade-off for the increased impedance and lower consumption obtained, the higher value resistors may also bring higher noise and sensibility to board contamination, and possibly frequency response changes (the increased R*C time constant due to parasitic capacitances can change the gain vs. frequency plot).

An example of an active low-pass filter using the NCS2008x operational amplifier can be found in Figure 31. The filter's 3 dB Bandwidth is approximately 25 KHz, followed by a -40 dB/dec roll-off as in Figure 32. Such filters with flat response in the sampled signal band are recommended as a front-end for ADC's to avoid aliasing.

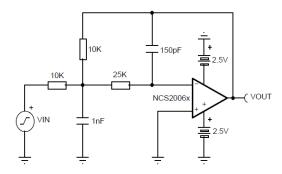


Figure 31. Second Order Active Low Pass Filter

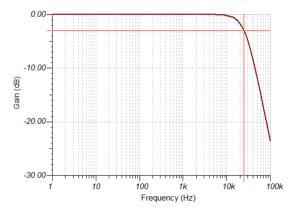


Figure 32. Filter's Frequency Response

Using the P-SPICE models provided by ON Semiconductor is recommended as a starting point for component selection, and then values can be further fine-tuned during bench testing the application.



SC-88A (SC-70-5/SOT-353) CASE 419A-02 **ISSUE L**

DATE 17 JAN 2013



- TES:
 DIMENSIONING AND TOLERANCING
 PER ANSI Y14.5M, 1982.
 CONTROLLING DIMENSION: INCH.
 419A-01 OBSOLETE. NEW STANDARD 3.
- 419A-02.
 DIMENSIONS A AND B DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS.

	INC	HES	MILLIN	IETERS
DIM	MIN	MAX	MIN	MAX
Α	0.071	0.087	1.80	2.20
В	0.045	0.053	1.15	1.35
С	0.031	0.043	0.80	1.10
D	0.004	0.012	0.10	0.30
G	0.026	BSC	0.65 BSC	
Н		0.004		0.10
J	0.004	0.010	0.10	0.25
K	0.004	0.012	0.10	0.30
N	0.008 REF		0.20	REF
S	0.079	0.087	2.00	2.20

GENERIC MARKING DIAGRAM*



XXX = Specific Device Code

= Date Code

= Pb-Free Package

(Note: Microdot may be in either location)

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "=", may or may not be present. Some products may not follow the Generic Marking.



0.50 0.0197 0.65 0.025 0.65 0.025 0.40 0.0157 1.9 mm 0.0748 SCALE 20:1

SOLDER FOOTPRINT

STYLE 1: PIN 1. BASE 2. EMITTER 3. BASE 4. COLLECTOR 5. COLLECTOR	STYLE 2: PIN 1. ANODE 2. EMITTER 3. BASE 4. COLLECTOR 5. CATHODE	STYLE 3: PIN 1. ANODE 1 2. N/C 3. ANODE 2 4. CATHODE 2 5. CATHODE 1	STYLE 4: PIN 1. SOURCE 1 2. DRAIN 1/2 3. SOURCE 1 4. GATE 1 5. GATE 2	STYLE 5: PIN 1. CATHODE 2. COMMON ANODE 3. CATHODE 2 4. CATHODE 3 5. CATHODE 4

5. COLLECTOR	5. CATHODE	5. CATHODE I	5. GATE 2	5. CATHODE 4
STYLE 6: PIN 1. EMITTER 2 2. BASE 2 3. EMITTER 1 4. COLLECTOR 5. COLLECTOR 2/BASE 1	STYLE 7: PIN 1. BASE 2. EMITTER 3. BASE 4. COLLECTOR 5. COLLECTOR	STYLE 8: PIN 1. CATHODE 2. COLLECTOR 3. N/C 4. BASE 5. EMITTER	STYLE 9: PIN 1. ANODE 2. CATHODE 3. ANODE 4. ANODE 5. ANODE	Note: Please refer to datasheet for style callout. If style type is not called out in the datasheet refer to the device datasheet pinout or pin assignment.

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DESCRIPTION:	SC-88A (SC-70-5/SOT-35	63)	PAGE 1 OF 1		

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TSOP-5 **CASE 483 ISSUE N**

DATE 12 AUG 2020









NOTES:

- DIMENSIONING AND TOLERANCING PER ASME
- CONTROLLING DIMENSION: MILLIMETERS.
 MAXIMUM LEAD THICKNESS INCLUDES LEAD FINISH
 THICKNESS. MINIMUM LEAD THICKNESS IS THE
 MINIMUM THICKNESS OF BASE MATERIAL.
- DIMENSIONS A AND B DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.15 PER SIDE. DIMENSION A. OPTIONAL CONSTRUCTION: AN ADDITIONAL
- TRIMMED LEAD IS ALLOWED IN THIS LOCATION. TRIMMED LEAD NOT TO EXTEND MORE THAN 0.2 FROM BODY.

	MILLIMETERS			
DIM	MIN	MAX		
Α	2.85	3.15		
В	1.35	1.65		
C	0.90	1.10		
D	0.25	0.50		
G	0.95	BSC		
Н	0.01	0.10		
J	0.10	0.26		
K	0.20	0.60		
М	0 °	10 °		
S	2.50	3.00		

SOLDERING FOOTPRINT*



^{*}For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

GENERIC MARKING DIAGRAM*





XXX = Specific Device Code XXX = Specific Device Code

= Assembly Location = Date Code = Year = Pb-Free Package

= Work Week W

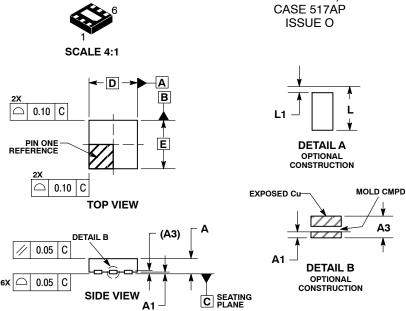
= Pb-Free Package

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DESCRIPTION:	TSOP-5		PAGE 1 OF 1

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UDFN6 1.6x1.6, 0.5P

DATE 26 OCT 2007

- NOTES:

 1. DIMENSIONING AND TOLERANCING PER
 ASME Y14.5M, 1994.

 2. CONTROLLING DIMENSION: MILLIMETERS.

 3. DIMENSION b APPLIES TO PLATED TERMINAL
 AND IS MEASURED BETWEEN 0.15 AND
- 0.30 mm FROM TERMINAL. COPLANARITY APPLIES TO THE EXPOSED PAD AS WELL AS THE TERMINALS.

	MILLIMETERS			
DIM	MIN	MAX		
Α	0.45	0.55		
A1	0.00	0.05		
А3	0.13	REF		
b	0.20	0.30		
D	1.60	BSC		
E	1.60	BSC		
е	0.50	BSC		
D2	1.10	1.30		
E2	0.45	0.65		
K	0.20			
L	0.20	0.40		
L1	0.00	0.15		

GENERIC MARKING DIAGRAM*



XX = Specific Device Code

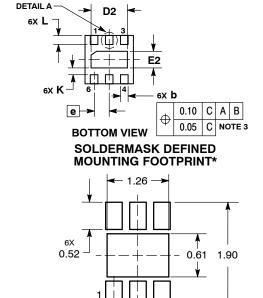
M = Date Code

■ = Pb-Free Package

(Note: Microdot may be in either location)

*This information is generic. Please refer to device data sheet for actual part marking.

Pb-Free indicator, "G" or microdot " ■", may or may not be present.



DIMENSIONS: MILLIMETERS

0.32

^{*}For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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0.50 PITCH



SOIC-8 NB CASE 751-07 **ISSUE AK**

DATE 16 FEB 2011



- NOTES:
 1. DIMENSIONING AND TOLERANCING PER
- ANSI Y14.5M, 1982.
 CONTROLLING DIMENSION: MILLIMETER.
- DIMENSION A AND B DO NOT INCLUDE MOLD PROTRUSION.
- MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE
- DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION.
- 751-01 THRU 751-06 ARE OBSOLETE. NEW STANDARD IS 751-07.

	MILLIMETERS		INC	HES
DIM	MIN	MAX	MIN	MAX
Α	4.80	5.00	0.189	0.197
В	3.80	4.00	0.150	0.157
С	1.35	1.75	0.053	0.069
D	0.33	0.51	0.013	0.020
G	1.27	7 BSC	0.050 BSC	
Н	0.10	0.25	0.004	0.010
J	0.19	0.25	0.007	0.010
K	0.40	1.27	0.016	0.050
М	0 °	8 °	0 °	8 °
N	0.25	0.50	0.010	0.020
S	5.80	6.20	0.228	0.244

SOLDERING FOOTPRINT*



^{*}For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

GENERIC MARKING DIAGRAM*



XXXXX = Specific Device Code = Assembly Location

= Wafer Lot = Year = Work Week

= Pb-Free Package



XXXXXX = Specific Device Code = Assembly Location Α

= Year ww = Work Week

= Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.

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SOIC-8 NB CASE 751-07 ISSUE AK

DATE 16 FEB 2011

STYLE 2: PIN 1. COLLECTOR, DIE, #1 2. COLLECTOR, #1 3. COLLECTOR, #2 4. COLLECTOR, #2 6. EMITTER, #2 7. BASE, #1 8. EMITTER, #1 STYLE 6: PIN 1. SOURCE 2. DRAIN 3. DRAIN 4. SOURCE 5. SOURCE 6. GATE 7. GATE 8. SOURCE STYLE 10: PIN 1. GROUND 2. BIAS 1 3. OUTPUT 4. GROUND 5. GROUND 6. PINS 2	STYLE 3: PIN 1. DRAIN, DIE #1 2. DRAIN, #1 3. DRAIN, #2 4. DRAIN, #2 5. GATE, #2 6. SOURCE, #2 7. GATE, #1 8. SOURCE, #1 STYLE 7: PIN 1. IMPUT 2. EXTERNAL BYPASS 3. THIRD STAGE SOURCE 4. GROUND 5. DRAIN 6. GATE 3 7. SECOND STAGE Vd 8. FIRST STAGE Vd STYLE 11: PIN 1. SOURCE 1 2. GATE 1 3. SOURCE 2 4. GATE 2	3. BASE, #2 4. COLLECTOR, #2 5. COLLECTOR, #2 6. EMITTER, #2 7. EMITTER, #1 8. COLLECTOR, #1 STYLE 12: PIN 1. SOURCE 2. SOURCE
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STYLE 18: PIN 1. ANODE 2. ANODE 3. SOURCE 4. GATE 5. DRAIN 6. DRAIN 7. CATHODE 8. CATHODE	STYLE 19: PIN 1. SOURCE 1 2. GATE 1 3. SOURCE 2 4. GATE 2 5. DRAIN 2 6. MIRROR 2 7. DRAIN 1 8. MIRROR 1	STYLE 20: PIN 1. SOURCE (N) 2. GATE (N) 3. SOURCE (P) 4. GATE (P) 5. DRAIN 6. DRAIN 7. DRAIN 8. DRAIN
STYLE 22: PIN 1. I/O LINE 1 2. COMMON CATHODE/VCC 3. COMMON CATHODE/VCC 4. I/O LINE 3 5. COMMON ANODE/GND 6. I/O LINE 4 7. I/O LINE 5 8. COMMON ANODE/GND	STYLE 23: PIN 1. LINE 1 IN 2. COMMON ANODE/GND 3. COMMON ANODE/GND 4. LINE 2 IN 5. LINE 2 OUT 6. COMMON ANODE/GND 7. COMMON ANODE/GND 8. LINE 1 OUT	STYLE 24: PIN 1. BASE 2. EMITTER 3. COLLECTOR/ANODE 4. COLLECTOR/ANODE 5. CATHODE 6. CATHODE 7. COLLECTOR/ANODE 8. COLLECTOR/ANODE
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STYLE 30: PIN 1. DRAIN 1 2. DRAIN 1 3. GATE 2 4. SOURCE 2 5. SOURCE 1/DRAIN 2 6. SOURCE 1/DRAIN 2 7. SOURCE 1/DRAIN 2 8. GATE 1		
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DESCRIPTION:	SOIC-8 NB		PAGE 2 OF 2

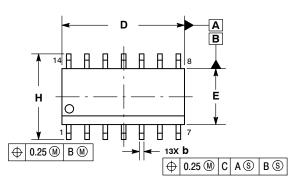
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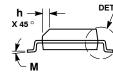
SOIC-14 NB CASE 751A-03 ISSUE L

DATE 03 FEB 2016









- NOTES:
 1. DIMENSIONING AND TOLERANCING PER
 - ASME Y14.5M, 1994.
 CONTROLLING DIMENSION: MILLIMETERS.
- DIMENSION b DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE PROTRUSION SHALL BE 0.13 TOTAL IN EXCESS OF AT
- MAXIMUM MATERIAL CONDITION.
 DIMENSIONS D AND E DO NOT INCLUDE MOLD PROTRUSIONS.
- 5. MAXIMUM MOLD PROTRUSION 0.15 PER SIDE

	MILLIN	IETERS	INC	HES
DIM	MIN	MAX	MIN	MAX
Α	1.35	1.75	0.054	0.068
A1	0.10	0.25	0.004	0.010
АЗ	0.19	0.25	0.008	0.010
b	0.35	0.49	0.014	0.019
D	8.55	8.75	0.337	0.344
Е	3.80	4.00	0.150	0.157
е	1.27	BSC	0.050 BSC	
Н	5.80	6.20	0.228	0.244
h	0.25	0.50	0.010	0.019
L	0.40	1.25	0.016	0.049
M	0 °	7°	0 °	7°

GENERIC MARKING DIAGRAM*



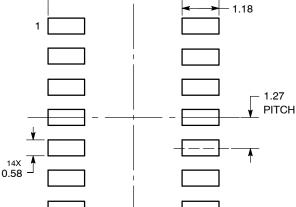
XXXXX = Specific Device Code Α = Assembly Location

WL = Wafer Lot Υ = Year WW = Work Week G = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator. "G" or microdot " ■". may or may not be present.

- 6.50 -14X

SOLDERING FOOTPRINT*



DIMENSIONS: MILLIMETERS

C SEATING PLANE

STYLES ON PAGE 2

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^{*}For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

SOIC-14 CASE 751A-03 ISSUE L

DATE 03 FEB 2016

STYLE 1: PIN 1. COMMON CATHODE 2. ANODE/CATHODE 3. ANODE/CATHODE 4. NO CONNECTION 5. ANODE/CATHODE 6. NO CONNECTION 7. ANODE/CATHODE 8. ANODE/CATHODE 9. ANODE/CATHODE 10. NO CONNECTION 11. ANODE/CATHODE 12. ANODE/CATHODE 13. NO CONNECTION 14. COMMON ANODE	STYLE 2: CANCELLED	STYLE 3: PIN 1. NO CONNECTION 2. ANODE 3. ANODE 4. NO CONNECTION 5. ANODE 6. NO CONNECTION 7. ANODE 8. ANODE 9. ANODE 10. NO CONNECTION 11. ANODE 12. ANODE 13. NO CONNECTION 14. COMMON CATHODE	STYLE 4: PIN 1. NO CONNECTION 2. CATHODE 3. CATHODE 4. NO CONNECTION 5. CATHODE 6. NO CONNECTION 7. CATHODE 8. CATHODE 9. CATHODE 10. NO CONNECTION 11. CATHODE 12. CATHODE 13. NO CONNECTION 14. COMMON ANODE
STYLE 5: PIN 1. COMMON CATHODE 2. ANODE/CATHODE 3. ANODE/CATHODE 4. ANODE/CATHODE 5. ANODE/CATHODE 6. NO CONNECTION 7. COMMON ANODE 8. COMMON CATHODE 9. ANODE/CATHODE 10. ANODE/CATHODE 11. ANODE/CATHODE 12. ANODE/CATHODE 13. NO CONNECTION 14. COMMON ANODE	STYLE 6: PIN 1. CATHODE 2. CATHODE 3. CATHODE 4. CATHODE 5. CATHODE 6. CATHODE 7. CATHODE 8. ANODE 9. ANODE 10. ANODE 11. ANODE 12. ANODE 13. ANODE 14. ANODE	STYLE 7: PIN 1. ANODE/CATHODE 2. COMMON ANODE 3. COMMON CATHODE 4. ANODE/CATHODE 5. ANODE/CATHODE 6. ANODE/CATHODE 7. ANODE/CATHODE 8. ANODE/CATHODE 9. ANODE/CATHODE 10. ANODE/CATHODE 11. COMMON CATHODE 12. COMMON ANODE 13. ANODE/CATHODE 14. ANODE/CATHODE	STYLE 8: PIN 1. COMMON CATHODE 2. ANODE/CATHODE 3. ANODE/CATHODE 4. NO CONNECTION 5. ANODE/CATHODE 6. ANODE/CATHODE 7. COMMON ANODE 8. COMMON ANODE 9. ANODE/CATHODE 10. ANODE/CATHODE 11. NO CONNECTION 12. ANODE/CATHODE 13. ANODE/CATHODE 14. COMMON CATHODE

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Micro8 CASE 846A-02 ISSUE K

DATE 16 JUL 2020









NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 2009.
- CONTROLLING DIMENSION: MILLIMETERS
- DIMENSION 6 DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE PROTRUSION SHALL BE 0.10 mm IN EXCESS OF MAXIMUM MATERIAL CONDITION.
- DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSION OR GATE BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.15 mm PER SIDE. DIMENSION E DOES NOT INCLUDE INTERLEAD FLASH OR PROTRUSION. INTERLEAD FLASH OR PROTRUSION SHALL NOT EXCEED 0.25 mm PER SIDE. DIMENSIONS D AND E ARE DETERMINED AT DATUM F.
- DATUMS A AND B ARE TO BE DETERMINED AT DATUM F.
- A1 IS DEFINED AS THE VERTICAL DISTANCE FROM THE SEATING PLANE TO THE LOWEST POINT ON THE PACKAGE BODY.



MOUNTING FOOTPRINT

DIM	MI	MILLIMETERS		
ויונע	MIN.	N□M.	MAX.	
Α	-	-	1.10	
A1	0.05	0.08	0.15	
b	0.25	0.33	0.40	
c	0.13	0.18	0.23	
D	2.90	3.00	3.10	
Ε	2.90	3.00	3.10	
е				
HE	4.75	4.90	5.05	
L	0.40	0.55	0.70	

GENERIC MARKING DIAGRAM*



XXXX = Specific Device Code Α = Assembly Location

Υ = Year W = Work Week = Pb-Free Package

(Note: Microdot may be in either location)

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "■", may or may not be present. Some products may not follow the Generic Marking.

STYLE 1:	STYLE 2:	STYLE 3:
PIN 1. SOURCE	PIN 1. SOURCE 1	PIN 1. N-SOURCE
SOURCE	2. GATE 1	2. N-GATE
SOURCE	3. SOURCE 2	3. P-SOURCE
4. GATE	4. GATE 2	4. P-GATE
DRAIN	5. DRAIN 2	5. P-DRAIN
DRAIN	6. DRAIN 2	6. P-DRAIN
7. DRAIN	7. DRAIN 1	7. N-DRAIN
8. DRAIN	8. DRAIN 1	8. N-DRAIN

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DESCRIPTION:	MICRO8		PAGE 1 OF 1

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DATE 17 FEB 2016

- NOTES.

 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.

 2. CONTROLLING DIMENSION: MILLIMETER.

 3. DIMENSION A DOES NOT INCLUDE MOLD
- FLASH, PROTRUSIONS OR GATE BURRS. MOLD FLASH OR GATE BURRS SHALL NOT EXCEED 0.15 (0.006) PER SIDE.
 DIMENSION B DOES NOT INCLUDE
- INTERLEAD FLASH OR PROTRUSION.
 INTERLEAD FLASH OR PROTRUSION SHALL
- INTERLEAD FLASH OR PROTRUSION SHALL NOT EXCEED 0.25 (0.010) PER SIDE.

 5. DIMENSION K DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.08 (0.003) TOTAL IN EXCESS OF THE K DIMENSION AT MAXIMUM MATERIAL CONDITION.

 6. TERMINAL NUMBERS ARE SHOWN FOR DEFERENCE ONLY.
- REFERENCE ONLY.
 DIMENSION A AND B ARE TO BE
- DETERMINED AT DATUM PLANE -W-.

	MILLIMETERS		INC	HES
DIM	MIN	MAX	MIN	MAX
Α	4.90	5.10	0.193	0.200
В	4.30	4.50	0.169	0.177
С		1.20		0.047
D	0.05	0.15	0.002	0.006
F	0.50	0.75	0.020	0.030
G	0.65	BSC	0.026 BSC	
Н	0.50	0.60	0.020	0.024
J	0.09	0.20	0.004	0.008
J1	0.09	0.16	0.004	0.006
K	0.19	0.30	0.007	0.012
K1	0.19	0.25	0.007	0.010
L	6.40 BSC		0.252	BSC
М	0°	8 °	0 °	8 °

GENERIC MARKING DIAGRAM*



= Assembly Location

= Wafer Lot ٧ = Year

W = Work Week

= Pb-Free Package

(Note: Microdot may be in either location)

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " ■", may or may not be present.

—	7.06
1	
	
	U 0.65 PITCH
, <u> </u>	→ → • • • • • • • • • • • • • • • • • • •
14X	
0.36 14X 1.26	DIMENSIONS: MILLIMETERS

SOLDERING FOOTPRINT

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DESCRIPTION:	TSSOP-14 WB		PAGE 1 OF 1

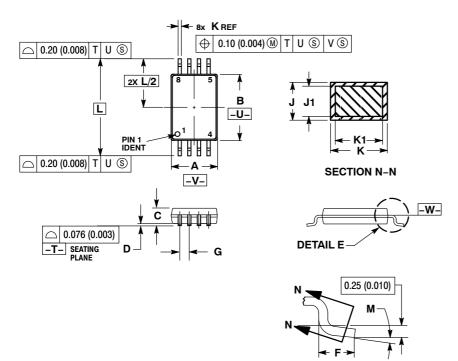
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TSSOP-8 CASE 948S-01 ISSUE C

DATE 20 JUN 2008



NOTES:

- DIMENSIONING AND TOLERANCING PER ANSI
- 714.5M, 1982.

 2. CONTROLLING DIMENSION: MILLIMETER.

 3. DIMENSION A DOES NOT INCLUDE MOLD FLASH.
 PROTRUSIONS OR GATE BURRS. MOLD FLASH OR GATE BURRS SHALL NOT EXCEED 0.15 (0.006) PER SIDE.
- (0.006) PEH SIDE.

 4. DIMENSION B DOES NOT INCLUDE INTERLEAD FLASH OR PROTRUSION. INTERLEAD FLASH OR PROTRUSION SHALL NOT EXCEED 0.25 (0.010) PER SIDE
- 5. TERMINAL NUMBERS ARE SHOWN FOR REFERENCE ONLY.
- DIMENSION A AND B ARE TO BE DETERMINED AT DATUM PLANE -W-.

	MILLIMETERS		INCHES		
DIM	MIN	MAX	MIN	MAX	
Α	2.90	3.10	0.114	0.122	
В	4.30 4.50 0.10		0.169	0.177	
С		1.10		0.043	
D	0.05	.05 0.15 0.0		0.006	
F	0.50	0.70 0.0	0.020	0.028	
G	0.65	0.65 BSC 0.026 B		BSC	
J	0.09	0.20	0.004	0.008	
J1	0.09	0.16	0.004	0.006	
K	0.19	0.30	0.007	0.012	
K1	0.19	0.25	0.007	0.010	
L	L 6.40 BSC		0.252 BSC		
M	0 °	8°	0.0	8 °	

GENERIC MARKING DIAGRAM*



XXX = Specific Device Code = Assembly Location Α

= Year WW = Work Week = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " ■", may or may not be present.

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DETAIL E



DOCUMENT NUMBER: 98AON00697D

PAGE 2 OF 2

ISSUE	REVISION	DATE
0	RELEASED FOR PRODUCTION.	18 APR 2000
Α	ADDED MARKING DIAGRAM INFORMATION. REQ. BY V. BASS.	13 JAN 2006
В	CORRECTED MARKING DIAGRAM PIN 1 LOCATION AND MARKING. REQ. BY C. REBELLO.	13 MAR 2006
С	REMOVED EXPOSED PAD VIEW AND DIMENSIONS P AND P1. CORRECTED MARKING INFORMATION. REQ. BY C. REBELLO.	20 JUN 2008
		-

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